Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/724,415	PAI ET AL.
Examiner	Art Unit

Richard Chan

2618

SEARCHED						
Class	Subclass	Date	Examiner			
455	181.1	7/6/2006	RC			
455	244.1	7/7/2006	RC			
455	230	7/7/2006	RC			
331	16	7/6/2006	RC			
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INTERFERENCE SEARCHED					
Subclass	Date	Examiner			

SEARCH NOT	TES STRATEGY	)
	DATE	EXMR
Calibration near4 cycle and time adj constant	7/7/2006	RC
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